FCC ID: 2BA4J-ZHD520R

Portable device
According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.
According to KDB447498 D01 General RF Exposure Guidance V06
The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:
[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]·[√f(GHZ)] ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
802.11b	2.412	7.94	6.22	8.5±1	9.5	8.91	<5	2.76834	3.00	YES
	2.437	8.32	6.79	8.5±1	9.5	8.91	<5	2.78264	3.00	YES
	2.462	8.11	6.47	8.5±1	9.5	8.91	<5	2.79688	3.00	YES
802.11g	2.412	8.69	7.40	8.5±1	9.5	8.91	<5	2.76834	3.00	YES
	2.437	8.33	6.81	8.5±1	9.5	8.91	<5	2.78264	3.00	YES
	2.462	8.42	6.95	8.5±1	9.5	8.91	<5	2.79688	3.00	YES
802.11n H20	2.412	8.68	7.38	8.5±1	9.5	8.91	<5	2.76834	3.00	YES
	2.437	8.32	6.79	8.5±1	9.5	8.91	<5	2.78264	3.00	YES
	2.462	8.51	7.10	8.5±1	9.5	8.91	<5	2.79688	3.00	YES
BLE 1M	2.402	1.92	1.56	2±1	3	2.00	<5	0.61847	3.00	YES
	2.440	2.27	1.69	2±1	3	2.00	<5	0.62334	3.00	YES
	2.480	2.3	1.70	2±1	3	2.00	<5	0.62843	3.00	YES
BLE 2M	2.402	1.92	1.56	2±1	3	2.00	<5	0.61847	3.00	YES
	2.440	2.27	1.69	2±1	3	2.00	<5	0.62334	3.00	YES
	2.480	2.3	1.70	2±1	3	2.00	<5	0.62843	3.00	YES

Conclusion:
For the max result : 2.79688≤3.0 for 1g SAR, SAR is not required.

Signature: **Date:** 2023-09-26

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